

Enable High Flux and Cost Efficient System

Acrich Chip on Board – MJT COB series S4WM-1062xx8036-0A900G3S-00001 (SAW81062A) S4WM-1062xx9036-0A900G3S-00001 (SAW91062A)





















Product Brief

Description

- The MJT series are LED arrays which provide High Flux and High Efficacy.
- It is especially designed for easy assembly of Lighting fixtures by eliminating reflow soldering process.
- It's thermal management is excellent than other power LED solutions with wider Metal area.
- The MJT series are ideal light sources for General Lighting applications including Replacement Lamps, Industrial & Commercial Lightings and other high Lumen required applications.

Features and Benefits

- Efficacy up to 162lm/W @5000K
- Size 13.5mm * 13.5mm
- MacAdam 2-step & 3-step binning
- Uniformed Shadow
- Excellent Thermal management
- RoHS compliant
- UL recognized component(E359235)

Key Applications

- Commercial Downlight
- Replacement lamps bulb, PAR, MR16
- Industrial
- Residential



Table 1. Product Selection Table

Reference Code	Color	Nominal	Part Number	CRI	
		CCT		Min	
		6500K	S4WM-1062658036-0A900G3S-00001		
	Cool White	5700K	S4WM-1062578036-0A900G3S-00001		
_		5000K	S4WM-1062508036-0A900G3S-00001		
SAW81062A	Neutral White	4000K	S4WM-1062408036-0A900G3S-00001	80	
		3500K	S4WM-1062358036-0A900G3S-00001		
	Warm White	3000K	S4WM-1062308036-0A900G3S-00001	_	
		2700K	S4WM-1062278036-0A900G3S-00001		
	Neutral White	4000K	S4WM-1062409036-0A900G3S-00001		
SAW91062A		3500K	S4WM-1062359036-0A900G3S-00001	- 90	
3AVV31002A	Warm White	3000K	S4WM-1062309036-0A900G3S-00001	90	
		2700K	S4WM-1062279036-0A900G3S-00001		



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Performance Characteristics

Table.2 Electro Optical Characteristics, T_i=85°C

		,			
ССТ (К) [1]	Typical Luminous Flux ^[2] Φ _V ^[3] (lm)	Typical Forward Voltage (V _F) ^[4]	CRI ^[5] , R _a	Viewing Angle (degrees) 20 ½	Part Number
Тур.	0.27A	0.27A	Min.	Тур.	
6500	1,445	34.1	80	118	S4WM-1062658036 -0A900G3S-00001
5700	1,455	34.1	80	118	S4WM-1062578036 -0A900G3S-00001
5000	1,475	34.1	80	118	S4WM-1062508036 -0A900G3S-00001
4000	1,465	34.1	80	118	S4WM-1062408036 -0A900G3S-00001
3500	1,435	34.1	80	118	S4WM-1062358036 -0A900G3S-00001
3000	1,415	34.1	80	118	S4WM-1062308036 -0A900G3S-00001
2700	1,365	34.1	80	118	S4WM-1062278036 -0A900G3S-00001
4000	1,230	34.1	90	118	S4WM-1062409036 -0A900G3S-00001
3500	1,205	34.1	90	118	S4WM-1062359036 -0A900G3S-00001
3000	1,190	34.1	90	118	S4WM-1062309036 -0A900G3S-00001
2700	1,140	34.1	90	118	S4WM-1062279036 -0A900G3S-00001
	Typ. 6500 5700 5000 4000 3500 3000 2700 4000 3500 3000	CCT (K) [1] Luminous Flux [2] Φ _V [3] (lm) Typ. 0.27A 6500 1,445 5700 1,455 5000 1,475 4000 1,465 3500 1,435 3000 1,415 2700 1,365 4000 1,230 3500 1,205 3000 1,190	CCT (K) [1] Luminous Flux [2] Φ _V [3] (lm) Typn Voltage (V _F) [4] Typ. 0.27A 0.27A 6500 1,445 34.1 5700 1,455 34.1 5000 1,475 34.1 4000 1,465 34.1 3500 1,435 34.1 2700 1,365 34.1 4000 1,230 34.1 3500 1,205 34.1 3000 1,190 34.1	CCT (K) [1] Luminous Flux [2] Φ _V [3] (lm) Typical Forward Voltage (V _F) [4] CRI [5], R _a Typ. 0.27A 0.27A Min. 6500 1,445 34.1 80 5700 1,455 34.1 80 5000 1,475 34.1 80 4000 1,465 34.1 80 3500 1,435 34.1 80 2700 1,365 34.1 80 4000 1,230 34.1 90 3500 1,205 34.1 90 3000 1,190 34.1 90	CCT (K) [1] Luminous Flux [2] $\Phi_V^{[3]}$ (lm) Typical Forward Voltage (V _F) [4] CRI [5], Ra Angle (degrees) 20 ½ Typ. 0.27A 0.27A Min. Typ. 6500 1,445 34.1 80 118 5700 1,455 34.1 80 118 5000 1,475 34.1 80 118 4000 1,465 34.1 80 118 3500 1,435 34.1 80 118 2700 1,365 34.1 80 118 4000 1,230 34.1 90 118 3500 1,205 34.1 90 118 3000 1,190 34.1 90 118

Notes:

- (1) Correlated Color Temperature is derived from the CIE 1931 Chromaticity diagram. Color coordinate : ± 0.005 , CCT $\pm 5\%$ tolerance.
- (2) Seoul Semiconductor maintains a tolerance of $\pm 7\%$ on flux and power measurements.
- (3) Φ_{V} is the total luminous flux output as measured with an integrating sphere.
- (4) Tolerance is $\pm 3\%$ on forward voltage measurements.
- (5) Tolerance is ± 2 on CRI measurements.

^{*} No values are provided by real measurement. Only for reference purpose.

Performance Characteristics

Table.3 Absolute Maximum Ratings

Dozemetez	Cumbal		Unit		
Parameter	Symbol	Min.	Тур.	Max.	Unit
Forward Current	I _F	-	0.27	0.54	Α
Power Dissipation	P_d	-	9.2	19.6	W
Junction Temperature	T_j	-	-	140	°C
Operating Temperature	T_{opr}	- 40	-	100	°C
Surface Temperature	T _S	- 40	-	105	°C
Storage Temperature	T_{stg}	- 40	-	105	°C
Thermal resistance (J to S) [1]	$R\theta_{J-S}$	-	1.00	-	K/W
ESD Sensitivity(HBM)		Class	3A JESD22-A	114-E	

Notes:

- (1) Thermal resistance : $R\theta_{J-S}$ (Junction / solder) At thermal resistance, J to S means junction to COB's substrate bottom.
- (2) LED's properties might be different from suggested values like above and below tables if operation condition will be exceeded our parameter range. Care is to be taken that power dissipation does not exceed the absolute maximum rating of the product.
- (3) Thermal resistance can be increased substantially depending on the heat sink design/operating condition, and the maximum possible driving current will decrease accordingly.
- (4) All measurements were made under the standardized environment of Seoul Semiconductor.

Fig 1. Color Spectrum, CRI80

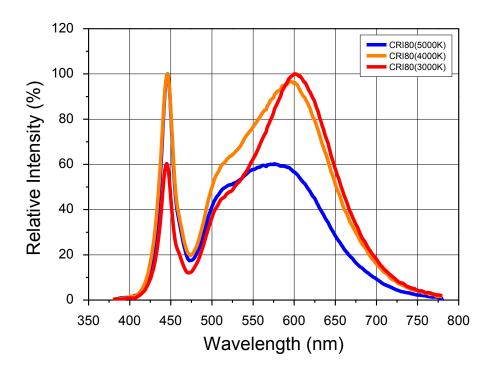


Fig 2. Color Spectrum, CRI90

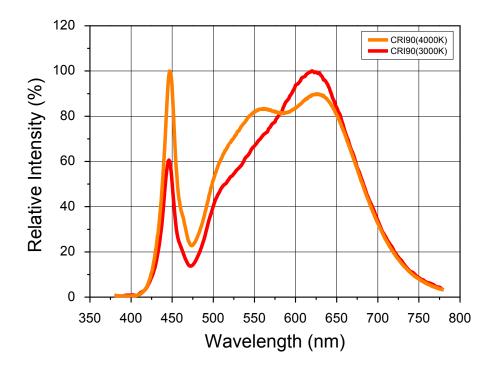


Fig 3. Radiant Pattern

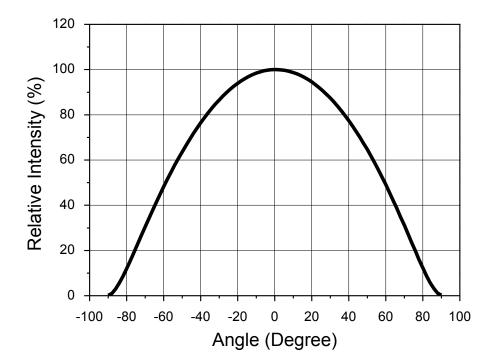


Fig 4. Forward Voltage vs. Forward Current, T_i=85 ℃

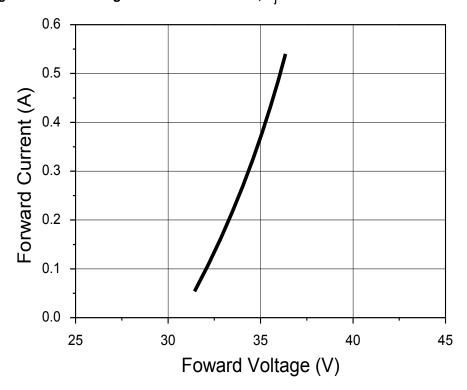
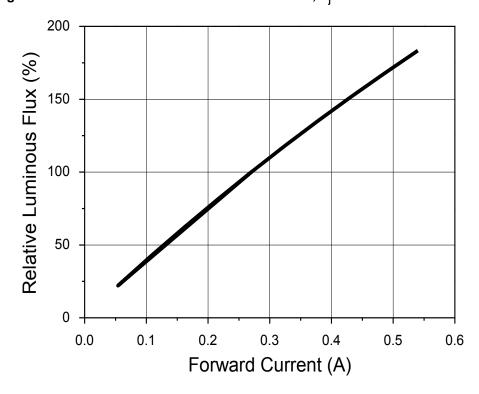


Fig 5. Forward Current vs. Relative Luminous Flux, T_i=85 ℃



S4WM-1062xxxx36-0A900G3S-00001(SAWx1062A)

- Chip on Board

Fig 6. Junction Temperature vs. Relative Luminous Flux, I_F=0.27A

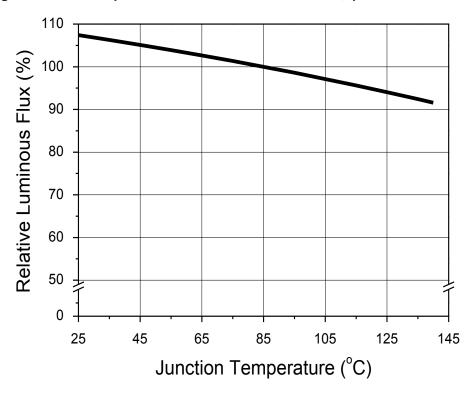


Fig 7. Junction Temperature vs. Forward Voltage, I_F=0.27A

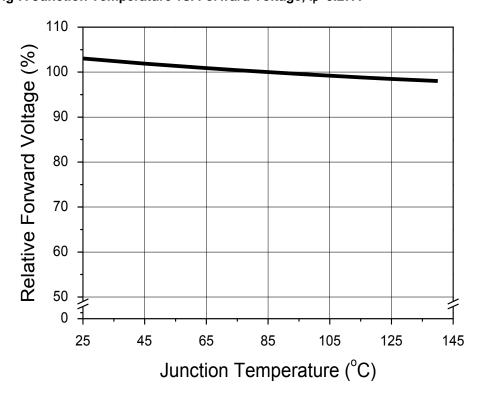


Fig 8. Junction Temperature vs. CIE x,y Shift, I_F=0.27A (CRI80, 5000K)

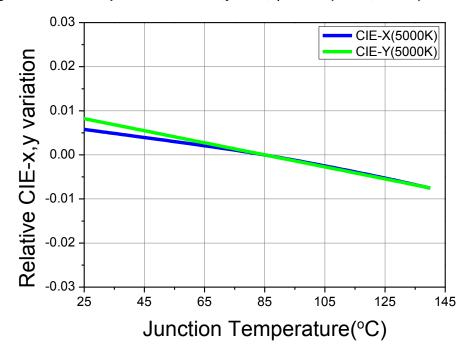


Fig 9. Junction Temperature vs. CIE x,y Shift, I_F=0.27A (CRI80, 4000K)

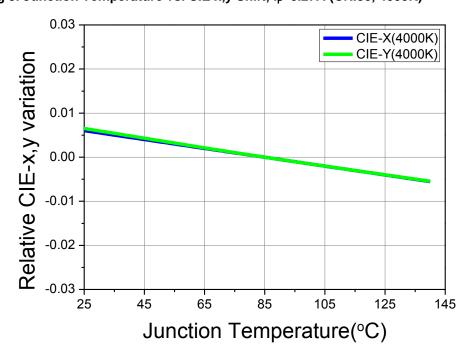


Fig 10. Junction Temperature vs. CIE x,y Shift, I_F=0.27A (CRI80, 3000K)

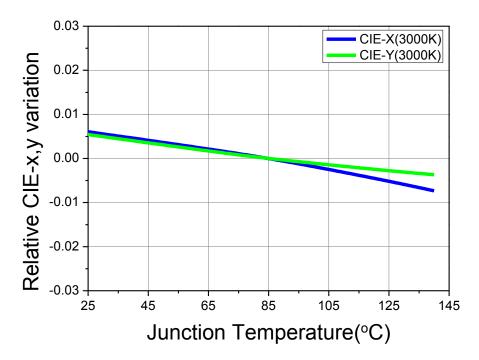


Fig 11. Junction Temperature vs. CIE x,y Shift, I_F=0.27A (CRI90, 4000K)

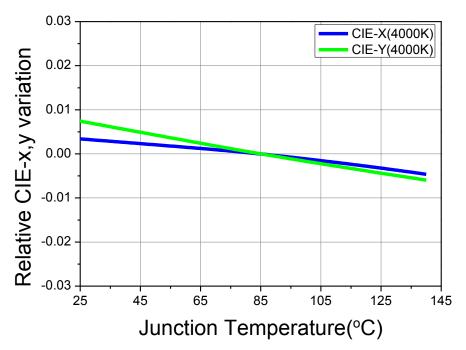


Fig 12. Junction Temperature vs. CIE x,y Shift, I_E=0.27A (CRI90, 3000K)

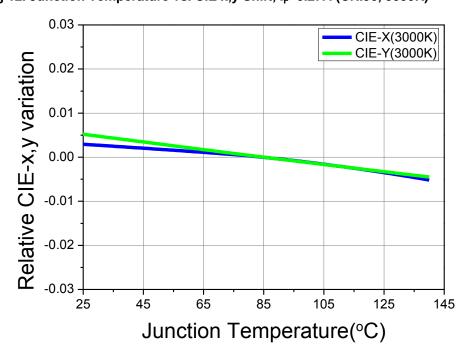


Fig 13. Forward current vs. CIE x,y Shift, T_i=85 ℃ (CRI80, 5000K)

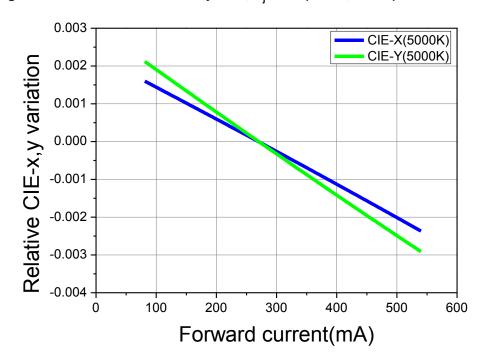


Fig 14. Forward current vs. CIE x,y Shift, T_i=85 ℃ (CRI80, 4000K)

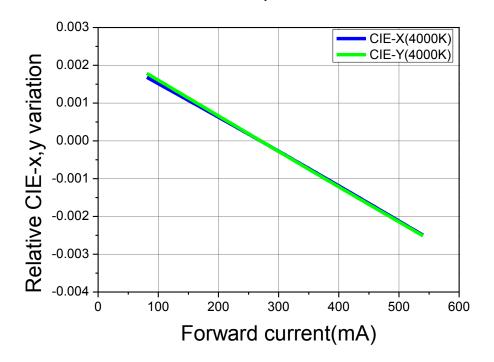


Fig 15. Forward current vs. CIE x,y Shift, T_i=85℃ (CRI80, 3000K)

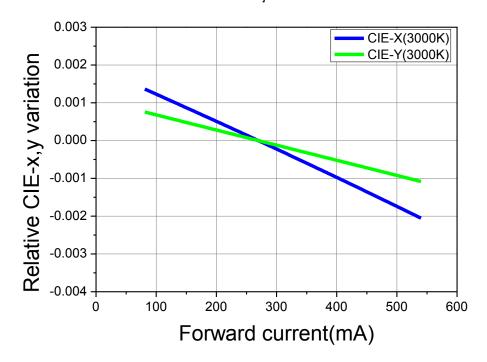


Fig 16. Forward current vs. CIE x,y Shift, T_i=85 ℃ (CRI90, 4000K)

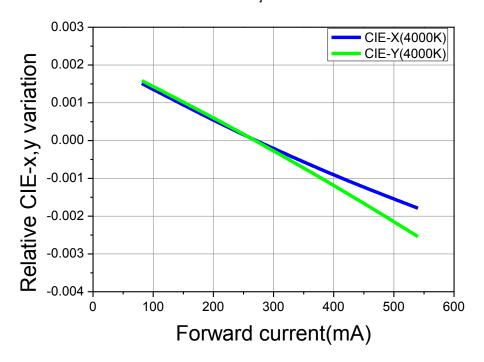


Fig 17. Forward current vs. CIE x,y Shift, T_i=85 ℃ (CRI90, 3000K)

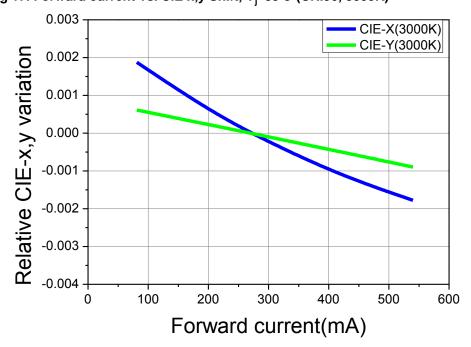
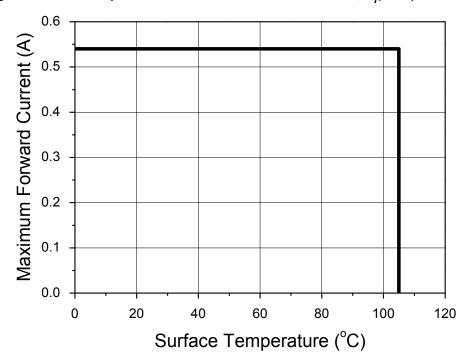


Fig 18. Surface Temperature vs. Maximum Forward Current, T_i(max.)=140°C



Color Bin Structure

Table 4. Bin Code description, T_i=85°C, I_F=0.27A

Part Number	Luminous Flux (Im)		Color Chromaticity		Typical Forward Voltage (V)		CRI			
(Reference Code)	Bin Code	Min.	Тур.	Bin Code	Typ. CCT	Bin Code	Min.	Max.	Bin Code	Min
	A9	1,330	1,445	AE3	6500K	G	32.5	36	8	80
	A9	1,340	1,455	BE3	5700K	G	32.5	36	8	80
\$4WM-	A9	1,355	1,475	CE3	5000K	G	32.5	36	8	80
1062xx ^[1] 8036- 0A900G3S- 00001	A9	1,350	1,465	EE3	4000K	G	32.5	36	8	80
(SAW81062A)	A9	1,320	1,435	FE3	3500K	G	32.5	36	8	80
	A9	1,300	1,415	GE3	3000K	G	32.5	36	8	80
	A9	1,255	1,365	HE3	2700K	G	32.5	36	8	80
	A9	1,130	1,230	EE2 EE3	4000K	G	32.5	36	9	90
S4WM- 1062xx ^[1] 9036- 0A900Gxx ^[2] - 00001 (SAW91062A)	A9	1,110	1,205	FE2 FE3	3500K	G	32.5	36	9	90
	A9	1,095	1,190	GE2 GE3	3000K	G	32.5	36	9	90
	A9	1,050	1,140	HE2 HE3	2700K	G	32.5	36	9	90

Notes:

(1) [1] and [2] indicate the CCT and the Ellipse bin size, respectively.

Color Bin Structure

CIE Chromaticity Diagram, T_i=85 ℃

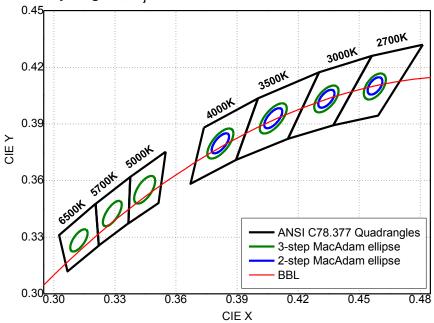


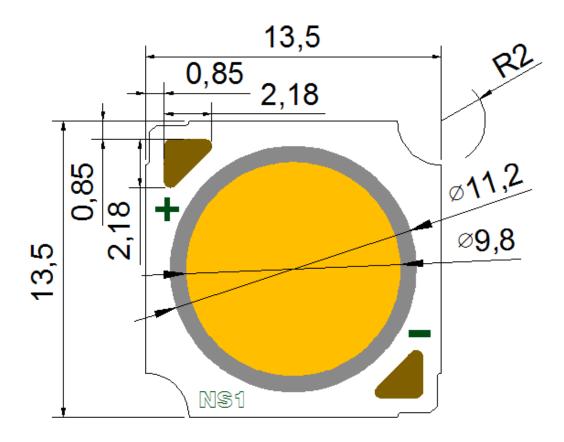
Table 5. 2-step/3-step MacAdam ellipse color bin definitions

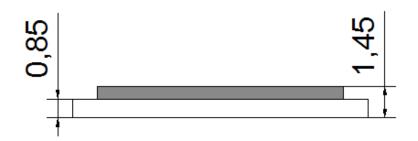
Color Region	ССТ	Cente	r Point	Major Axis	Minor Axis	Rotation Angle (θ)	
	(K)	CIE x	CIE y	(a)	(b)		
	6500	0.3123	0.3283	0.00669	0.00285	58.38	
	5700	0.3287	0.3425	0.00760	0.00296	59.46	
3-step	5000	0.3446	0.3551	0.00822	0.00354	59.62	
MacAdam	4000	0.3818	0.3797	0.00939	0.00402	54.00	
ellipse	3500	0.4078	0.393	0.00951	0.00417	52.97	
	3000	0.4339	0.4033	0.00834	0.00408	53.17	
	2700	0.4578	0.4101	0.00774	0.00411	57.28	
Color Region	ССТ	Cente	r Point	Major Axis	Minor Axis	Rotation Angle	
	(K)	CIE x	CIE y	(a)	(b)	(θ)	
	4000	0.3818	0.3797	0.00626	0.00268	54.00	
2-step MacAdam	3500	0.4078	0.393	0.00634	0.00278	52.97	
ellipse	3000	0.4339	0.4033	0.00556	0.00272	53.17	
	2700	0.4578	0.4101	0.00516	0.00274	57.28	

Notes:

- (1) The chromaticity center refers to ANSI C78.377:2015.
- (2) (a), (b), and (θ) indicate the major axis length, the minor axis length, and the rotation angle from the X axis of the ellipse bin, respectively.
- (3) It's possible to deliver 2-step bin up to 4000K.

Mechanical Dimensions

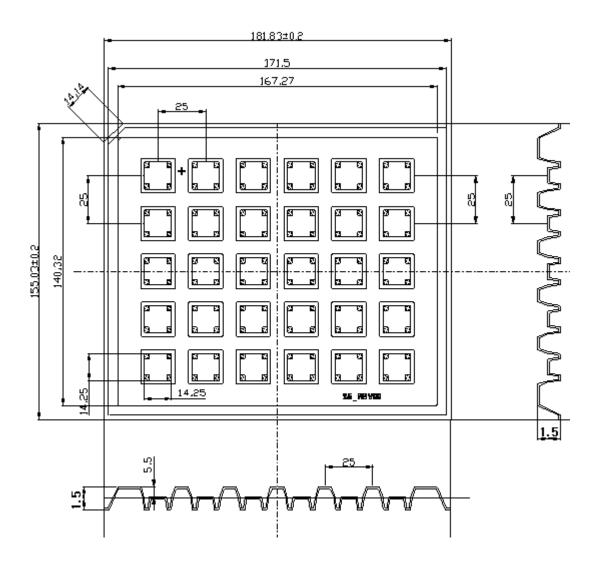




Notes:

- (1) All dimensions are in millimeters.
- (2) Scale: none
- (3) Undefined tolerance is ± 0.2 mm

Packaging Specification



Notes:

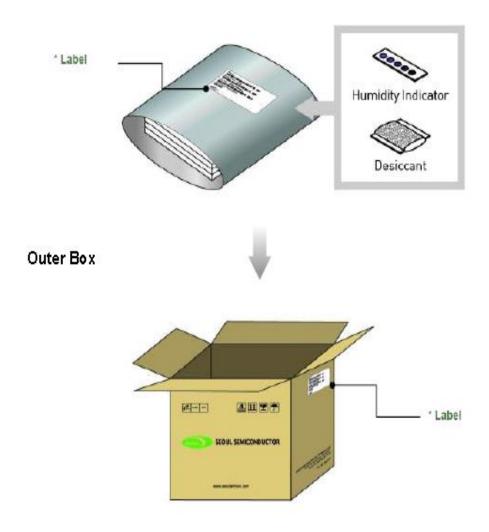
(1) Quantity: 30pcs/Tray

(2) All dimensions are in millimeters (tolerance : $\pm 0.3)\,$

(3) Scale none

Packaging Specification

Aluminum Bag



Notes:

(1) Heat Sealed after packing (Use Zipper Bag)

(2) Quantity: 1Tray(30pcs) /Bag

(3) Smallest packing quantity: 3Bags(90pcs) / small box



Product Nomenclature

Table 5. Part Numbering System

Part Number Code	Description	Part Number	Value
X ₁	Company	S	Seoul Semiconductor
X ₂	Level of Integration	4	СОВ
X ₃ X ₄	Technology	WM	MJT White
X ₅ X ₆ X ₇ X ₈	LES + Series and Parallel	1062	
X ₉ X ₁₀	CCT	xx	
X ₁₁ X ₁₂	CRI	xx	
X ₁₃ X ₁₄	Vf	36	
X ₁₅ X ₁₆ X ₁₇	Characteristic code Flux Rank	0A9	
X ₁₈ X ₁₉ X ₂₀	Characteristic code Vf Rank	00G	
X ₂₁ X ₂₂	Characteristic code Color Step	xS	3S = 3step ellipse 2S = 2step ellipse
X ₂₃ X ₂₄	Туре	00	
X ₂₅ X ₂₆ X ₂₇	Internal code	001	

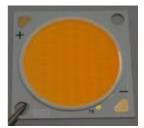
Handling of Silicone Resin for LEDs

(1) During processing, mechanical stress on the surface should be minimized as much as possible. Sharp objects of all types should not be used to pierce the sealing compound.



(2) In general, LEDs should only be handled from the side. By the way, this also applies to LEDs without a silicone sealant, since the surface can also become scratched.





- (3) Silicone differs from materials conventionally used for the manufacturing of LEDs. These conditions must be considered during the handling of such devices. Compared to standard encapsulants, silicone is generally softer, and the surface is more likely to attract dust. As mentioned previously, the increased sensitivity to dust requires special care during processing. In cases where a minimal level of dirt and dust particles cannot be guaranteed, a suitable cleaning solution must be applied to the surface after the soldering of wire.
- (4) Seoul Semiconductor suggests using isopropyl alcohol for cleaning. In case other solvents are used, it must be assured that these solvents do not dissolve the package or resin. Ultrasonic cleaning is not recommended. Ultrasonic cleaning may cause damage to the LED.
- (5) Please do not mold this product into another resin (epoxy, urethane, etc) and do not handle this product with acid or sulfur material in sealed space.
- (6) Avoid leaving fingerprints on silicone resin parts.

Precaution for Use

(1) Storage

To avoid the moisture penetration, we recommend storing LEDs in a dry box with a desiccant. The recommended storage temperature range is $5\,^{\circ}$ C to $30\,^{\circ}$ C and a maximum humidity of RH50%.

(2) Use Precaution after Opening the Packaging

Use SMT techniques properly when you solder the LED as separation of the lens may affect the light output efficiency.

Pay attention to the following:

- a. Recommend conditions after opening the package
 - Sealing / Temperature : 5 ~ 30 °C Humidity : less than RH60%
- b. If the package has been opened more than 4 week(MSL_2a) or the color of the desiccant changes, components should be dried for 10-24hr at 65 ± 5 °C
- (3) Radioactive exposure is not considered for the products listed here in.
- (4) Gallium arsenide is used in some of the products listed in this publication. These products are dangerous if they are burned or shredded in the process of disposal. It is also dangerous to drink the liquid or inhale the gas generated by such products when chemically disposed of.
- (5) This device should not be used in any type of fluid such as water, oil, organic solvent and etc. When washing is required, IPA (Isopropyl Alcohol) should be used.
- (6) When the LEDs are in operation the maximum current should be decided after measuring the package temperature.
- (7) LEDs must be stored in a clean environment. We recommend LEDs store in nitrogen-filled container.
- (8) The appearance and specifications of the product may be modified for improvement without notice.
- (9 Long time exposure of sunlight or occasional UV exposure will cause lens discoloration.
- (10) Attaching LEDs, do not use adhesive that outgas organic vapor.
- (11) The driving circuit must be designed to allow forward voltage only when it is ON or OFF. If the reverse voltage is applied to LED, migration can be generated resulting in LED damage.
- (12) Please do not touch any of the circuit board, components or terminals with bare hands or metal while circuit is electrically active.



Precaution for Use

(13) VOCs (Volatile organic compounds) emitted from materials used in the construction of fixtures can penetrate silicone encapsulants of LEDs and discolor when exposed to heat and photonic energy. The result can be a significant loss of light output from the fixture. Knowledge of the properties of the materials selected to be used in the construction of fixtures can help prevent these issues.

(14) LEDs are sensitive to Electro-Static Discharge (ESD) and Electrical Over Stress (EOS). Below is a list of suggestions that Seoul Semiconductor purposes to minimize these effects.

a. ESD (Electro Static Discharge)

Electrostatic discharge (ESD) is the defined as the release of static electricity when two objects come into contact. While most ESD events are considered harmless, it can be an expensive problem in many industrial environments during production and storage. The damage from ESD to an LEDs may cause the product to demonstrate unusual characteristics such as:

- Increase in reverse leakage current lowered turn-on voltage
- Abnormal emissions from the LED at low current

The following recommendations are suggested to help minimize the potential for an ESD event. One or more recommended work area suggestions:

- Ionizing fan setup
- ESD table/shelf mat made of conductive materials
- ESD safe storage containers

One or more personnel suggestion options:

- Antistatic wrist-strap
- Antistatic material shoes
- Antistatic clothes

Environmental controls:

- Humidity control (ESD gets worse in a dry environment)



Precaution for Use

b. EOS (Electrical Over Stress)

Electrical Over-Stress (EOS) is defined as damage that may occur when an electronic device is subjected to a current or voltage that is beyond the maximum specification limits of the device. The effects from an EOS event can be noticed through product performance like:

- Changes to the performance of the LED package
 (If the damage is around the bond pad area and since the package is completely encapsulated the package may turn on but flicker show severe performance degradation.)
- Changes to the light output of the luminaire from component failure
- Components on the board not operating at determined drive power

Failure of performance from entire fixture due to changes in circuit voltage and current across total circuit causing trickle down failures. It is impossible to predict the failure mode of every LED exposed to electrical overstress as the failure modes have been investigated to vary, but there are some common signs that will indicate an EOS event has occurred:

- Damaged may be noticed to the bond wires (appearing similar to a blown fuse)
- Damage to the bond pads located on the emission surface of the LED package (shadowing can be noticed around the bond pads while viewing through a microscope)
- Anomalies noticed in the encapsulation and phosphor around the bond wires.
- This damage usually appears due to the thermal stress produced during the EOS event.
- c. To help minimize the damage from an EOS event Seoul Semiconductor recommends utilizing:
 - A surge protection circuit
 - An appropriately rated over voltage protection device
 - A current limiting device



Company Information

Published by

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Company Information

Seoul Semiconductor (www.SeoulSemicon.com) manufacturers and packages a wide selection of light emitting diodes (LEDs) for the automotive, general illumination/lighting, Home appliance, signage and back lighting markets. The company is the world's fifth largest LED supplier, holding more than 10,000 patents globally, while offering a wide range of LED technology and production capacity in areas such as "nPola", "Acrich", the world's first commercially produced AC LED, and "Acrich MJT - Multi-Junction Technology" a proprietary family of high-voltage LEDs.

The company's broad product portfolio includes a wide array of package and device choices such as Acrich and Acirch2, high-brightness LEDs, mid-power LEDs, side-view LEDs, and through-hole type LEDs as well as custom modules, displays, and sensors.

Legal Disclaimer

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Revision History

Revision	Date	Page	Remarks
0.0	2017.09.28	All	Initial release of data sheet applied